Search Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	der
10/664,571	CHEN ET AL.	
Examiner	Art Unit	•
Jason Mitchell	2193	

SEARCHED			
Class	Subclass	Date	Examiner
717	101- 103,120- 124,171- 173	5/16/2006	V
713	100	5/16/2006	Ş
709	220-226	5/16/2006	^
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INT	INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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